1. (CURRENTLY AMENDED) A non-contact tester for electronic circuits, comprising in combination:

an electronic circuit which includes ~~at least one~~ a plurality of wireless i/o cells and means for sending and receiving signals via each of the ~~at least one~~ wireless i/o cells, and a wireless i/o cell being provided for each contact point on the electronic circuit to be tested; and

an independent scanning head having ~~at least one~~ a plurality of wireless i/o cells compatible with the ~~at least one~~ wireless i/o cells on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit, and the number of wireless i/o cells on the independent scanning head corresponding in a one to one relationship with the number of wireless i/o cells on the electronic circuit being tested.

2. (CANCELED)

3. (CANCELED)

4. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via each of the ~~at least one~~ wireless i/o cells is a radio frequency interface.

5. (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 4, wherein the radio frequency interface includes at least one transmitter and at least one receiver.

6. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via each of the ~~at least one~~ wireless i/o cells is an optical interface.

7. (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 6, the optical interface includes at least one light emitter and at least one light receptor.

8. (CURRENTLY AMENDED) The non-contact tester for electronic circuits as defined in claim 1, wherein the means for sending and receiving signals via each of the ~~at least one~~ wireless i/o cells is a magnetic interface.

9. (PREVIOUSLY PRESENTED) The non-contact tester for electronic circuits as defined in claim 8, wherein the magnetic interface includes a magnetic detector and a magnetic generator.

10. (WITHDRAWN) A method of testing for electronic circuits, comprising the steps of:

providing a non-contact tester having an electronic circuit which includes at least one wireless i/o cell and means for sending and receiving signals via the at least one wireless i/o cell;

providing an independent scanning head having at least one wireless i/o cell compatible with the at least one wireless i/o cell on the electronic circuit, such that data may be exchanged with the electronic circuit to confirm proper functioning of the electronic circuit; and

testing the electronic circuit to confirm proper functioning of the electric circuit.

11. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a radio frequency interface.

12. (WITHDRAWN) The method as defined in claim 11, wherein the radio frequency interface includes at least one transmitter and at least one receiver.

13. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is an optical interface.

14. (WITHDRAWN) The method as defined in claim 13, the optical interface includes at least one light emitter and at least one light receptor.

15. (WITHDRAWN) The method as defined in claim 10, wherein the means for sending and receiving signals via the at least one wireless i/o cell is a magnetic interface.

16. (WITHDRAWN) The method defined in claim 15, wherein the magnetic interface includes a magnetic detector and a magnetic generator.